Doc No. : LITD 09 (24954) WC Draft IS 14700 (Part 1/Sec 1):2024 Identical with IEC TR 61000-1-1: 2023 February 2024

BUREAU OF INDIAN STANDARDS

DRAFT FOR COMMENTS ONLY

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मसौदा भारतीय मानक विद्युत चुंबकीय संगतता (ई एम सी) – भाग 1: सामान्य – अनुभाग 1: आधारभूत परिभाषाओं और शर्तों का अनुप्रयोग एवं व्याख्या (पहला पुनरीक्षण)

Draft Indian Standard

Electromagnetic Compatibility (EMC) – Part 1: General – Section 1: Application and Interpretation of Fundamental Definitions and Terms (First Revision)

ICS 33.100.01

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LITD 09 Electromagnetic Compatibility Last Date for Comments: 27 April 2024. Sectional Committee

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NATIONAL FOREWORD

(Formal clauses will be added later)

This Draft Indian Standard (Part 1/Section 1) (First Revision) which is identical with IEC TR 61000-1-1:2023 'Electromagnetic compatibility (EMC) - Part 1-1: General - Application and interpretation of fundamental definitions and terms' issued by the International Electrotechnical Commission (IEC) *will be* adopted by the Bureau of Indian Standards on the recommendation of the Electromagnetic Compatibility Sectional Committee (LITD 09) and approval of the Electronics and Information Technology Division Council.

IS 14700 (Part 1/Sec1) was first published in 2000 and was identical with IEC TR 61000-1-1:1992. This first revision has been undertaken to align it with the latest version of with IEC 61000-1-1:2023 'Electromagnetic compatibility (EMC) - Part 1-1: General - Application and interpretation of fundamental definitions and terms.

The text of IEC Standard *will be* approved as suitable for publication as an Indian Standard without deviations. Certain conventions are however not identical to those used in Indian Standards. Attention is particularly drawn to the following:

- a) Wherever the words 'International Standard' appears referring to this standard, they should be read as 'Indian Standard'.
- b) Comma (,) has been used as a decimal marker while in Indian Standards, the current practice is to use a point (.) as the decimal marker.

In this adopted standard, reference appears to certain International Standards for which Indian Standards also exist. The corresponding Indian Standards, which are to be substituted in their respective places, are listed below along with their degree of equivalence for the editions indicated. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies:

International standards	Corresponding Indian standards	Degree of Equivalence
IEC 60050-161:1990,International	IS 1885 (Part 85) : 2003	Identical
Electrotechnical Vocabulary	Electrotechnical vocabulary: Part 85	
(IEV) – Part 161:Electromagnetic	electromagnetic compatibility	
compatibility		

For the purpose of deciding whether a particular requirement of this standard is complied with, the final value, observed or calculated, expressing the result of a test or analysis, shall be rounded off in accordance with IS 2:2022 'Rules for rounding off numerical values (*Second Revision*)'. The number of significant places retained in the rounded off value should be same as that of the specified value in this standard.

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SCOPE OF IEC 61000-1-1:2023

"This part of IEC 61000, which is a Technical Report, aims to describe and interpret various terms considered to be of basic importance to concepts and practical application in the design and evaluation of electromagnetically compatible equipment and systems.

In addition, attention is drawn to the distinction between electromagnetic compatibility (EMC) tests carried out in a standardized set-up and those carried out at other locations, for example at premises where a device, equipment or system is manufactured or at the location where a device, equipment or system is installed (in situ tests or measurements)."

Note: - The Technical content of this document has not been enclosed as these are identical with the corresponding IEC Standard. For details please refer to IEC 61000-1-1:2023 or kindly contact.

Head,

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